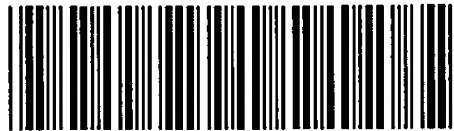


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	09/786,063	HENNEN ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Bob A. Phunkulh	2616	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
370/503, 509, 516, 517, 518, 519, 522 (text serch -see attachement)	8/31/2005	BAP
EAST (Text search)	8/31/2005	BAP
Consult with Wellington Chin	12/18/2006	BAP
EAST (text search)	11/15/2006	BAP